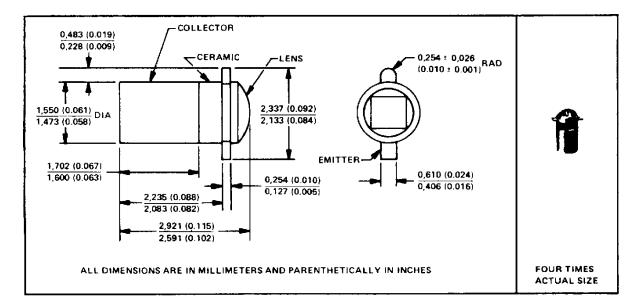
TIL601 THRU TIL604, LS600, LS602, LS611 THRU LS619 N-P-N PLANAR SILICON PHOTOTRANSISTORS

SODS026A D1971, NOVEMBER 1974-REVISED SEPTEMBER 1989

DESIGNED FOR HIGH-DENSITY READ OUT

- Hermetically-Sealed Pill Package
- Recommended for Application in Character Recognition, Tape and Card Readers, Velocity Indicators, and Encoders
- Unique Package Design Allows for Assembly into Printed Circuit Boards
- Spectrally and Mechanically Compatible with TIL23 thru TIL25
- Saturation Level Directly Compatible with Most TTL
- TIL604HR2[†] Includes High-Reliability Processing and Lot Acceptance (See TIL604HR2 for Summary of Processing)

mechanical data



¹All electrical and mechanical specifications for the TIL24 also apply for TIL24HR2



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electrical characteristics at 25 °C case temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	TYPE	MIN	TYP	MAX	UNIT
V(BR)CEO	Collector-emitter breakdown voltage	$I_{C} = 100 \mu A, E_{e} = 0$	All	50			٧
V(BR)ECO	Emitter-collector breakdown voltage	$I_E = 100 \mu A, E_e = 0$	All	7			V
1 _D	Dark current	V _{CE} = 30 V, E _e = 0	All			25	nΑ
		$V_{CE} = 30 \text{ V}, E_e = 0,$	All		3		μА
		T _C = 100 °C					μ.
ار	Light current		TIL601	0.5		3	
			TIL602	2		5	
			TIL603	4		8	
			TIL604	7			
			LS600	0.8			
			LS602	0.5			
		$V_{CE} = 5 \text{ V}.$ $E_e = 20 \text{ mW/cm}^2$	LS611	0.5	1	2	
		See Note 2	′ LS612	1	2	3	mA
		See Note 2	LS613	2	3	4	
			LS614	3	4	5	
			LS615	4	5	6	
			LS616	5	6	7	
			LS617	6	_ 7	8	
			L\$618	7	В	9	
			LS619	8	9		
VCE(sat)	Collector-emitter saturation voltage	I _C = 0.4 mA, E _e = 20 mW/cm ² See Note 2	΄ All	0.15			٧

NOTES: 1. Derate linearly to 125 °C at the rate of 0.5 mW/°C.

switching characteristics at 25 °C case temperature

	PARAMETER	TEST CONDITIONS	TYP	UNIT
t,	Rise time	V _{CC} = 30 V, I _L = 800 дА,	8	
Ţ.f.	Fall time	$R_1 = 1 k\Omega$, See Figure 1	6	1 μ5

Irradiance (E_e) is the radiant power per unit area incident upon a surface. For this measurement, the source is an unfiltered tungsten linear-filament lamp operating at a color temperature of 2870 K.

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PARAMETER MEASUREMENT INFORMATION See Note A OUTPUT See Note B TEST CIRCUIT OUTPUT VOLTAGE WAVEFORM

- NOTES: A. Input irradiance is supplied by a pulsed gallium arsenide infrared emitter with rise and fall times of less than 50 ns. Incident irradiation is adjusted for $I_L = 800 \ \mu A$.
 - B. Output waveform is monitored on an oscilloscope with the following characteristics: $t_r \le 25$ ns, $R_{in} \ge 1$ M Ω , $C_{in} \le 20$ pF.

FIGURE 1

TYPICAL APPLICATION DATA 20 V 2N3330 2N3330 PHOTOTRANSISTOR 2,2 kΩ OUTPUT

FIGURE 2. LOW-LEVEL DETECTOR AND PREAMPLIFIER

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TYPICAL APPLCIATION DATA _ 12 V 10 kΩ **≥ 22** kΩ TL710 V_{CC1} 680 pF = 100 μF OUTPUT 10 kΩ Vccz TIL23 GND PHOTO-TRANSISTOR 10 kΩ $10\;k\Omega$

FIGURE 3. OPTICALLY COUPLED AMPLIFIER

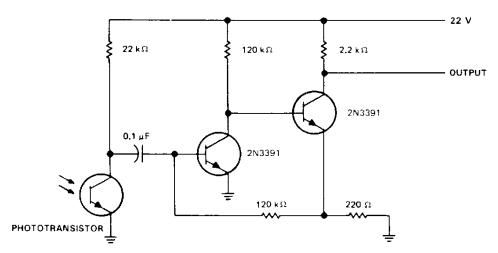
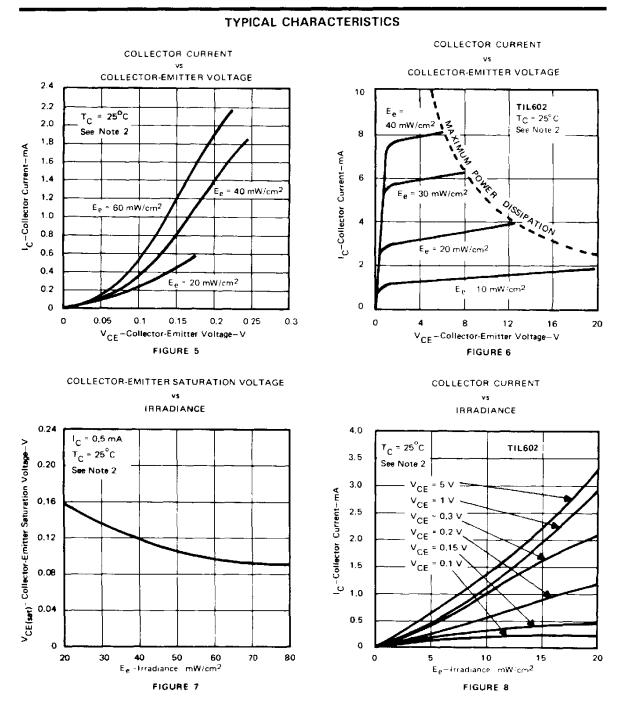


FIGURE 4. LIGHT PULSE DETECTOR

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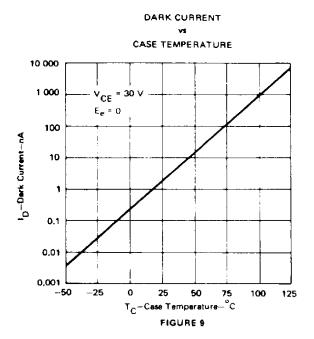


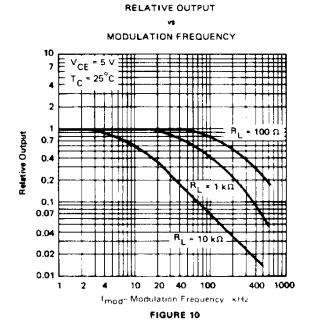
NOTE 2. Irradiance (Eg.) is the radiant power unit area incident upon a surface. For this measurement, the source is an unfiltered tungsten linear-filament lamp operating at a color temperature of 2870 K.



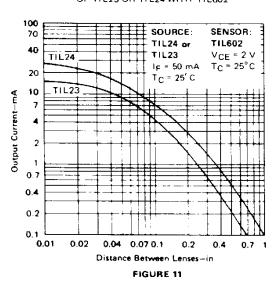
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TYPICAL CHARACTERISTICS

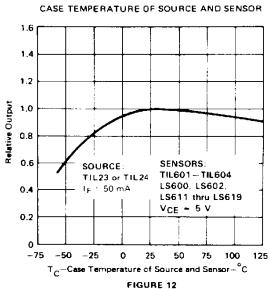




COUPLING CHARACTERISTICS OF TIL23 OR TIL24 WITH TIL602

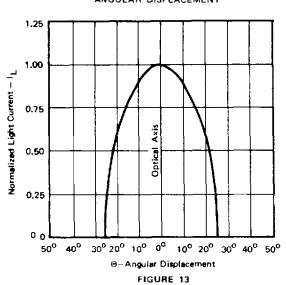


RELATIVE OUTPUT vs CASE TEMPERATURE OF SOURCE AND SENSOR

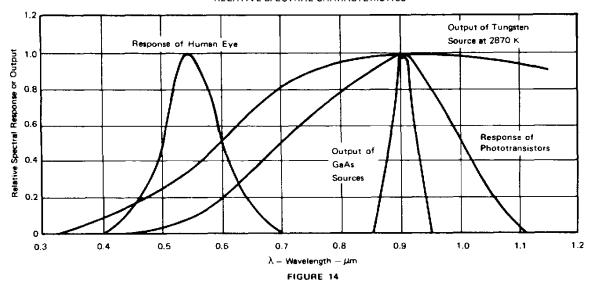


TYPICAL CHARACTERISTICS

NORMALIZED LIGHT CURRENT
vs
ANGULAR DISPLACEMENT



RELATIVE SPECTRAL CHARACTERISTICS



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